



**THE DATASHEET OF  
8535AGI-21LFT**



**General Description**



The ICS8535I-21 is a low skew, high performance 1-to-2 LVCMOS/LVTTL-to-3.3V LVPECL fanout buffer and a member of the HiPerClockS™ family of High Performance Clock Solutions from IDT. The ICS8535I-21 has two single-ended clock inputs. The

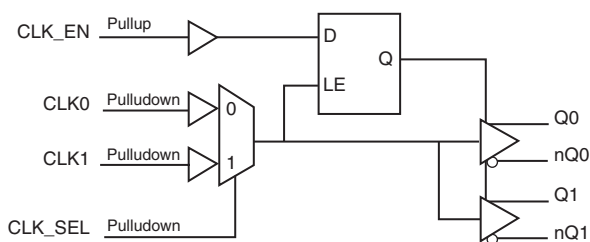
single-ended clock input accepts LVCMOS or LVTTL input levels and translate them to 3.3V LVPECL levels. The clock enable is internally synchronized to eliminate runt clock pulses on the output during asynchronous assertion/deassertion of the clock enable pin.

Guaranteed output and part-to-part skew characteristics make the ICS8535I-21 ideal for those applications demanding well defined performance and repeatability.

**Features**

- Two differential 3.3V LVPECL outputs
- Selectable CLK0 or CLK1 inputs for redundant and multiple frequency fanout applications
- CLK0 or CLK1 can accept the following input levels: LVCMOS or LVTTL
- Maximum output frequency: 266MHz
- Translates LVCMOS and LVTTL levels to 3.3V LVPECL levels
- Output skew: 20ps (maximum)
- Part-to-part skew: 300ps (maximum)
- Propagation delay: 1.6ns (maximum)
- Additive phase jitter, RMS: 0.03ps (typical)
- 3.3V operating supply
- -40°C to 85°C ambient operating temperature
- Available in lead-free (RoHS 6) package

**Block Diagram**



**Pin Assignment**

V <sub>EE</sub>	1	14	V <sub>CC</sub>
CLK_EN	2	13	Q0
CLK_SEL	3	12	nQ0
CLK0	4	11	nc
V <sub>EE</sub>	5	10	Q1
CLK1	6	9	nQ1
V <sub>CC</sub>	7	8	V <sub>CC</sub>

**ICS8535I-21**

**14 Lead TSSOP**

**4.40mm x 5.0mm x 0.925mm package body**

**G Package**

**Top View**

**Table 1. Pin Descriptions**

Number	Name	Type		Description
1, 5	V <sub>EE</sub>	Power		Negative supply pins.
2	CLK_EN	Input	Pullup	Synchronizing clock enable. When HIGH, clock outputs follow clock input. When LOW, Qx outputs are forced low, nQx outputs are forced high. LVCMOS/LVTTL interface levels.
3	CLK_SEL	Input	Pulldown	Clock select input. When HIGH, selects CLK1 input. When LOW, selects CLK0 input. LVCMOS/LVTTL interface levels.
4, 6	CLK0, CLK1	Input	Pulldown	Single-ended clock inputs. LVCMOS/LVTTL interface levels.
7, 8, 14	V <sub>CC</sub>	Power		Power supply pins.
9, 10	nQ1, Q1	Output		Differential output pair. LVPECL interface levels.
11	nc	Unused		No connect.
12, 13	nQ0, Q0	Output		Differential output pair. LVPECL interface levels.

NOTE: *Pullup* and *Pulldown* refer to internal input resistors. See Table 2, *Pin Characteristics*, for typical values.

**Table 2. Pin Characteristics**

Symbol	Parameter	Test Conditions	Minimum	Typical	Maximum	Units
C <sub>IN</sub>	Input Capacitance			4		pF
R <sub>PULLUP</sub>	Input Pullup Resistor			51		kΩ
R <sub>PULLDOWN</sub>	Input Pulldown Resistor			51		kΩ

## Function Tables

Table 3A. Control Input Function Table

Inputs			Outputs	
CLK_EN	CLK_SEL	Selected Source	Q0, Q1	nQ0, nQ1
0	0	CLK0	Disabled; Low	Disabled; High
0	1	CLK1	Disabled; Low	Disabled; High
1	0	CLK0	Enabled	Enabled
1	1	CLK1	Enabled	Enabled

After CLK\_EN switches, the clock outputs are disabled or enabled following a rising and falling input clock edge as shown in Figure 1. In the active mode, the state of the outputs are a function of the CLK0 and CLK1 inputs as described in Table 3B.

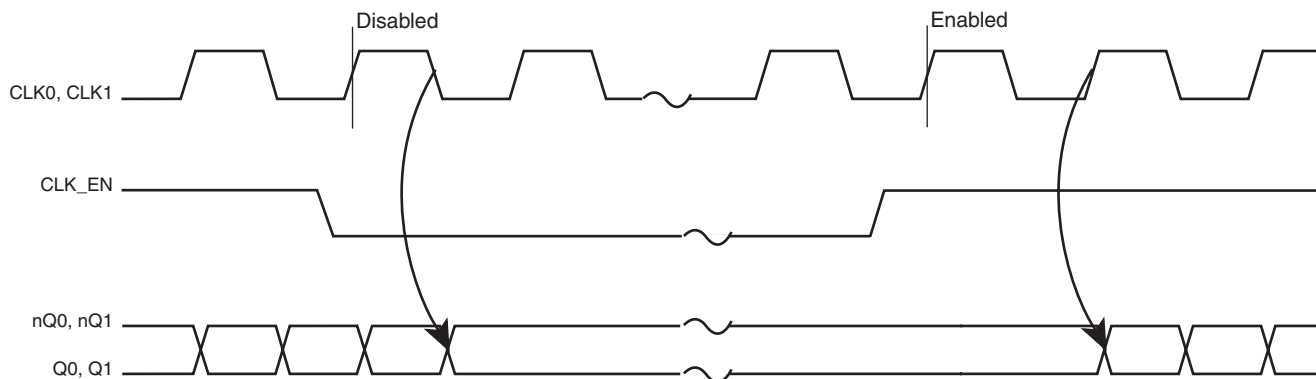


Figure 1. CLK\_EN Timing Diagram

Table 3B. Clock Input Function Table

Inputs	Outputs	
	Q0, Q1	nQ0, nQ1
0	LOW	HIGH
1	HIGH	LOW

## Absolute Maximum Ratings

NOTE: Stresses beyond those listed under *Absolute Maximum Ratings* may cause permanent damage to the device. These ratings are stress specifications only. Functional operation of product at these conditions or any conditions beyond those listed in the *DC Characteristics* or *AC Characteristics* is not implied. Exposure to absolute maximum rating conditions for extended periods may affect product reliability.

Item	Rating
Supply Voltage, $V_{CC}$	4.6V
Inputs, $V_I$	-0.5V to $V_{CC} + 0.5V$
Outputs, $I_O$ Continuous Current Surge Current	50mA 100mA
Package Thermal Impedance, $\theta_{JA}$	103.8°C/W (0 mps)
Storage Temperature, $T_{STG}$	-65°C to 150°C

## DC Electrical Characteristics

**Table 4A. Power Supply DC Characteristics,  $V_{CC} = 3.3V \pm 5\%$ ,  $T_A = -40^\circ C$  to  $85^\circ C$**

Symbol	Parameter	Test Conditions	Minimum	Typical	Maximum	Units
$V_{CC}$	Positive Supply Voltage		3.135	3.3	3.465	V
$I_{EE}$	Power Supply Current				50	mA

**Table 4B. LVCMOS/LVTTL DC Characteristics,  $V_{CC} = 3.3V \pm 5\%$ ,  $T_A = -40^\circ C$  to  $85^\circ C$**

Symbol	Parameter	Test Conditions	Minimum	Typical	Maximum	Units
$V_{IH}$	Input High Voltage		2		$V_{CC} + 0.3$	V
$V_{IL}$	Input Low Voltage	CLK0, CLK1	-0.3		1.3	V
		CLK_EN, CLK_SEL	-0.3		0.8	V
$I_{IH}$	Input High Current	CLK0, CLK1, CLK_SEL	$V_{CC} = V_{IN} = 3.465$		150	$\mu A$
		CLK_EN	$V_{CC} = V_{IN} = 3.465$		5	$\mu A$
$I_{IL}$	Input Low Current	CLK0, CLK1, CLK_SEL	$V_{CC} = 3.465V, V_{IN} = 0V$	-5		$\mu A$
		CLK_EN	$V_{CC} = 3.465V, V_{IN} = 0V$	-150		$\mu A$

**Table 4C. LVPECL DC Characteristics,  $V_{CC} = 3.3V \pm 5\%$ ,  $T_A = -40^{\circ}C$  to  $85^{\circ}C$** 

Symbol	Parameter	Test Conditions	Minimum	Typical	Maximum	Units
$V_{OH}$	Output High Current; NOTE 1		$V_{CC} - 1.4$		$V_{CC} - 0.9$	$\mu A$
$V_{OL}$	Output Low Current; NOTE 1		$V_{CC} - 2.0$		$V_{CC} - 1.7$	$\mu A$
$V_{SWING}$	Peak-to-Peak Output Voltage Swing		0.6		1.0	V

NOTE 1: Outputs termination with  $50\Omega$  to  $V_{CC} - 2V$ .

## AC Electrical Characteristics

**Table 5. AC Characteristics,  $V_{CC} = 3.3V \pm 5\%$ ,  $T_A = -40^{\circ}C$  to  $85^{\circ}C$** 

Parameter	Symbol	Test Conditions	Minimum	Typical	Maximum	Units
$f_{MAX}$	Output Frequency				266	MHz
$t_{PD}$	Propagation Delay; NOTE 1	$f \leq 266MHz$	1.0		1.6	ns
$f_{jit}$	Buffer Additive Phase Jitter, RMS; refer to Additive Phase Jitter Section; NOTE 2	156.25MHz, Integration Range: 12kHz – 20MHz		0.03		ps
$t_{sk(o)}$	Output Skew; NOTE 3, 4				20	ps
$t_{sk(pp)}$	Part-to-Part Skew; NOTE 4, 5				300	ps
$t_R / t_F$	Output Rise/Fall Time	20% to 80% @ 50MHz	300		600	ps
odc	Output Duty Cycle	$f \leq 200MHz$	45		55	%

NOTE: Electrical parameters are guaranteed over the specified ambient operating temperature range, which is established when the device is mounted in a test socket with maintained transverse airflow greater than 500 lfm. The device will meet specifications after thermal equilibrium has been reached under these conditions.

All parameters measured at  $f \leq 266MHz$  unless noted otherwise.

NOTE 1: Measured from  $V_{CC}/2$  of the input to the differential output crossing point. The part does not add jitter.

NOTE 2: Driving only one input clock.

NOTE 3: Defined as skew between outputs at the same supply voltage and with equal load conditions.

Measured at  $V_{CC}/2$  of the input to the differential output crossing point.

NOTE 4: This parameter is defined in accordance with JEDEC Standard 65.

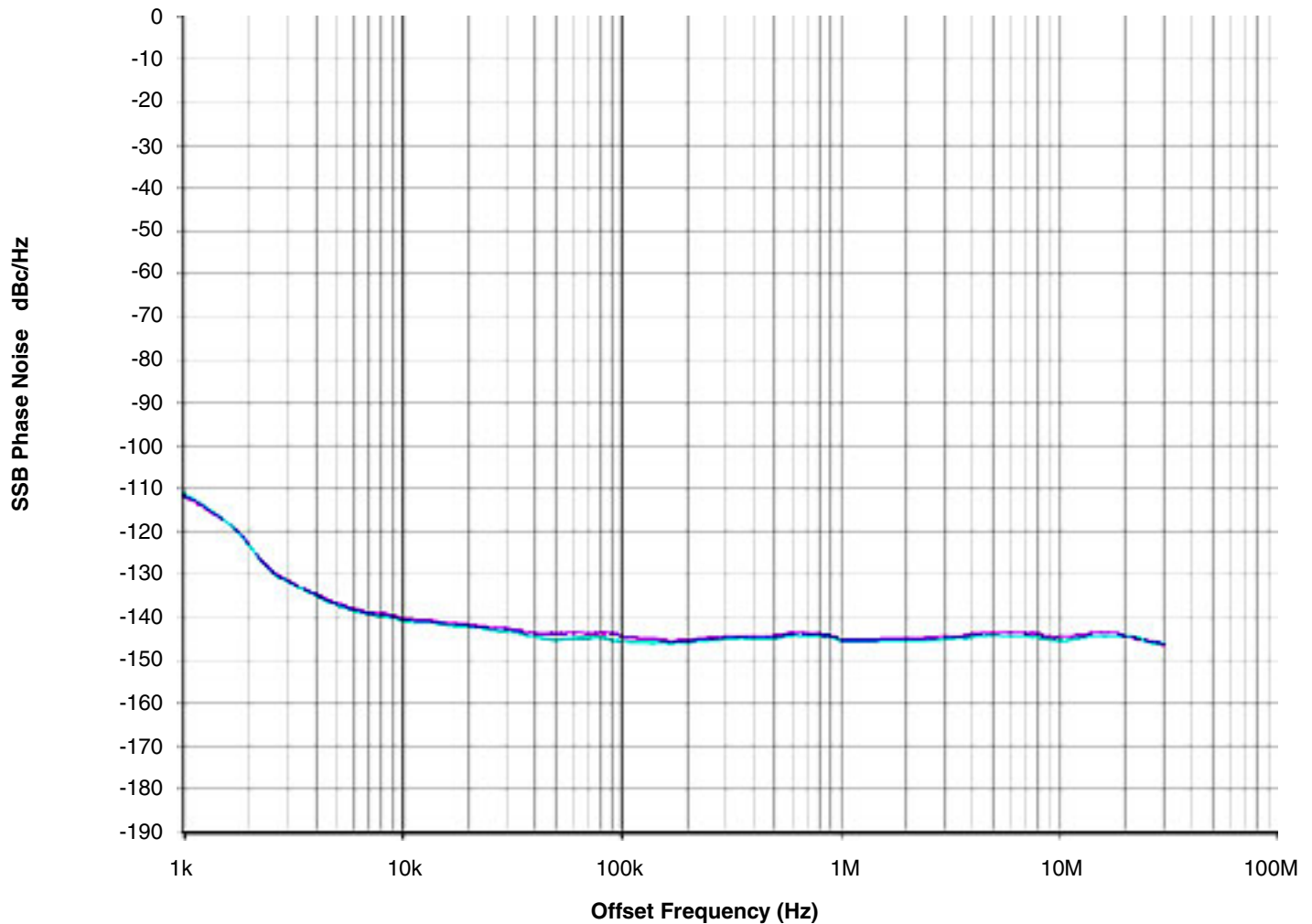
NOTE 5: Defined as skew between outputs on different devices operating at the same supply voltage and with equal load conditions.

Using the same type of inputs on each device, the outputs are measured at the differential cross points.

## Additive Phase Jitter

The spectral purity in a band at a specific offset from the fundamental compared to the power of the fundamental is called the ***dBc Phase Noise***. This value is normally expressed using a Phase noise plot and is most often the specified plot in many applications. Phase noise is defined as the ratio of the noise power present in a 1Hz band at a specified offset from the fundamental frequency to the power value of the fundamental. This ratio is expressed in decibels (dBm) or a ratio of the power in the 1Hz band

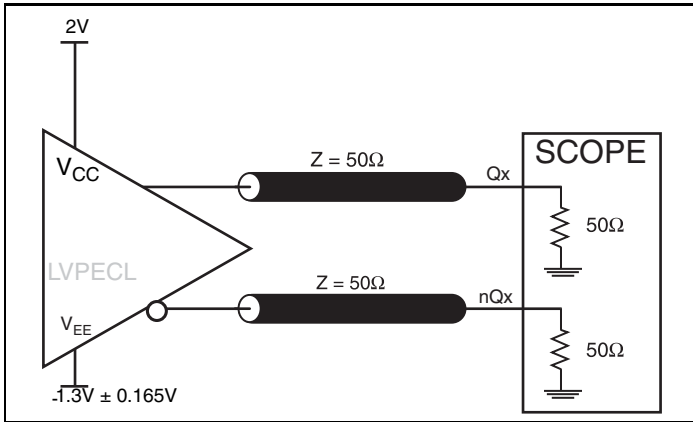
to the power in the fundamental. When the required offset is specified, the phase noise is called a ***dBc*** value, which simply means dBm at a specified offset from the fundamental. By investigating jitter in the frequency domain, we get a better understanding of its effects on the desired application over the entire time record of the signal. It is mathematically possible to calculate an expected bit error rate given a phase noise plot.



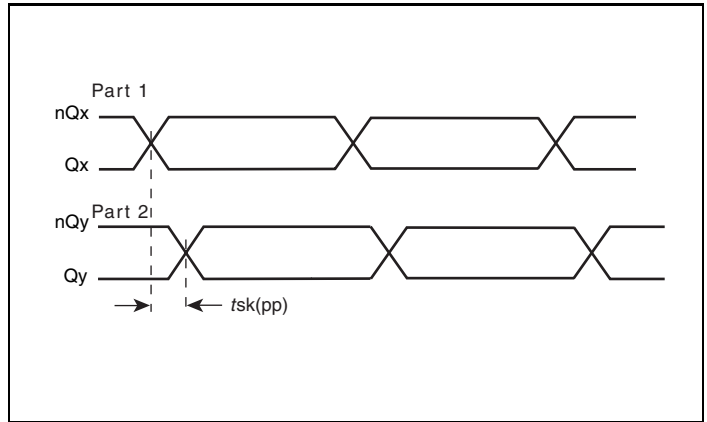
As with most timing specifications, phase noise measurements has issues relating to the limitations of the equipment. Often the noise floor of the equipment is higher than the noise floor of the

device. This is illustrated above. The device meets the noise floor of what is shown, but can actually be lower. The phase noise is dependent on the input source and measurement equipment.

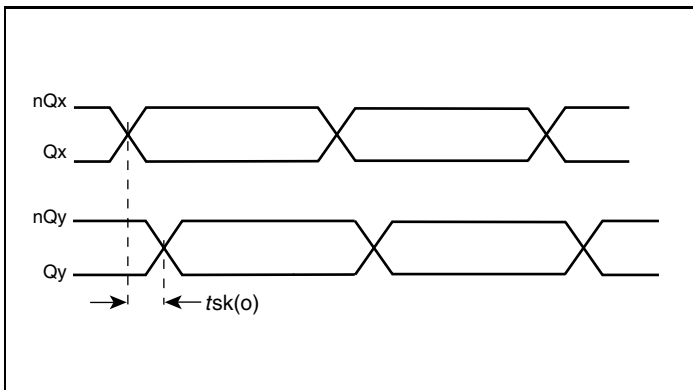
### Parameter Measurement Information



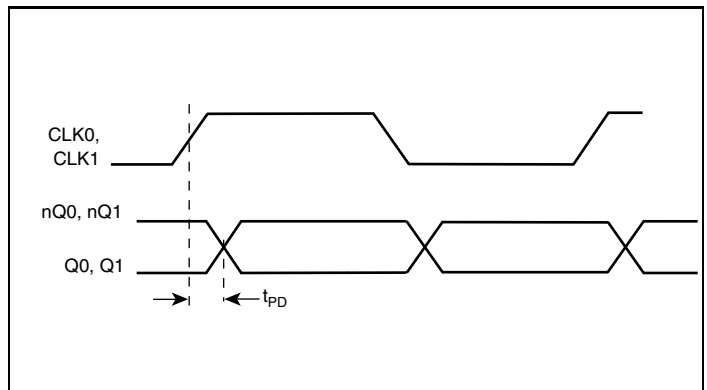
3.3V LVPECL Output Load AC Test Circuit



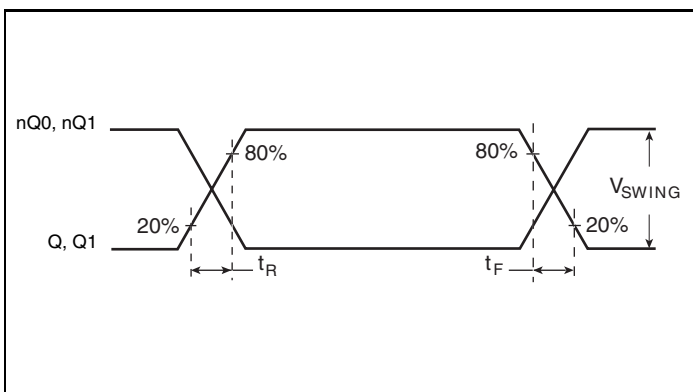
Part-to-Part Skew



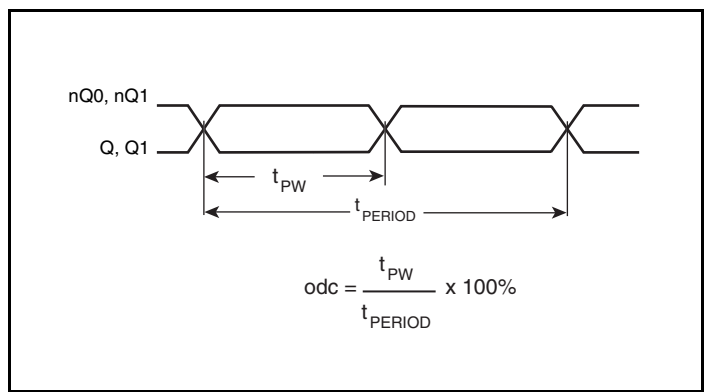
Output Skew



Propagation Delay



Output Rise/Fall Time



Output Duty Cycle/Pulse Width/Period

## Application Information

### Recommendations for Unused Input and Output Pins

#### Inputs:

##### CLK Inputs

For applications not requiring the use of a clock input, it can be left floating. Though not required, but for additional protection, a 1k $\Omega$  resistor can be tied from the CLK input to ground.

##### LVCMOS Control Pins

All control pins have internal pull-ups or pull-downs; additional resistance is not required but can be added for additional protection. A 1k $\Omega$  resistor can be used.

#### Outputs:

##### LVPECL Outputs

All unused LVPECL outputs can be left floating. We recommend that there is no trace attached. Both sides of the differential output pair should either be left floating or terminated.

### Termination for 3.3V LVPECL Outputs

The clock layout topology shown below is a typical termination for LVPECL outputs. The two different layouts mentioned are recommended only as guidelines.

FOUT and nFOUT are low impedance follower outputs that generate ECL/LVPECL compatible outputs. Therefore, terminating resistors (DC current path to ground) or current sources must be used for functionality. These outputs are designed to drive 50 $\Omega$

transmission lines. Matched impedance techniques should be used to maximize operating frequency and minimize signal distortion. *Figures 2A and 2B* show two different layouts which are recommended only as guidelines. Other suitable clock layouts may exist and it would be recommended that the board designers simulate to guarantee compatibility across all printed circuit and clock component process variations.

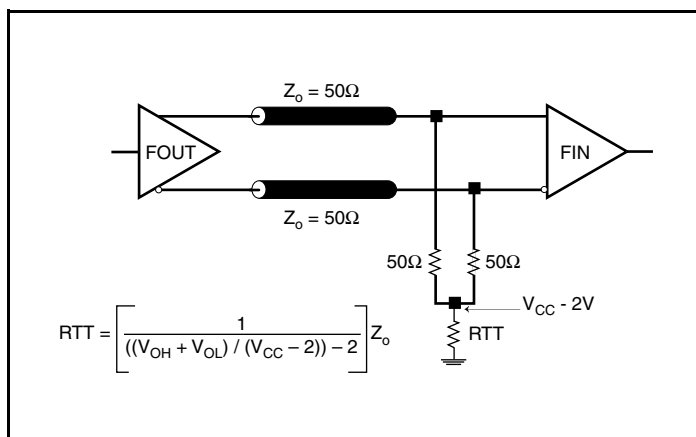


Figure 2A. 3.3V LVPECL Output Termination

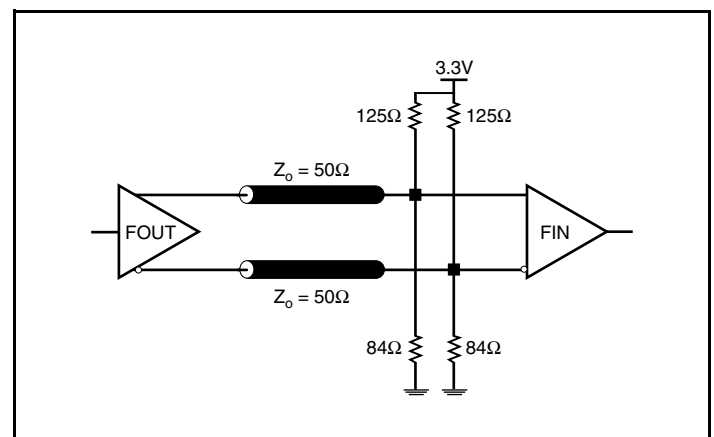


Figure 2B. 3.3V LVPECL Output Termination

### Schematic Example

Figure 3 shows a schematic example of the ICS8535I-21. The decoupling capacitors should be physically located near the power pin. For ICS8535I-21, the unused clock outputs can be left floating.

pin. For ICS8535I-21, the unused clock outputs can be left floating.

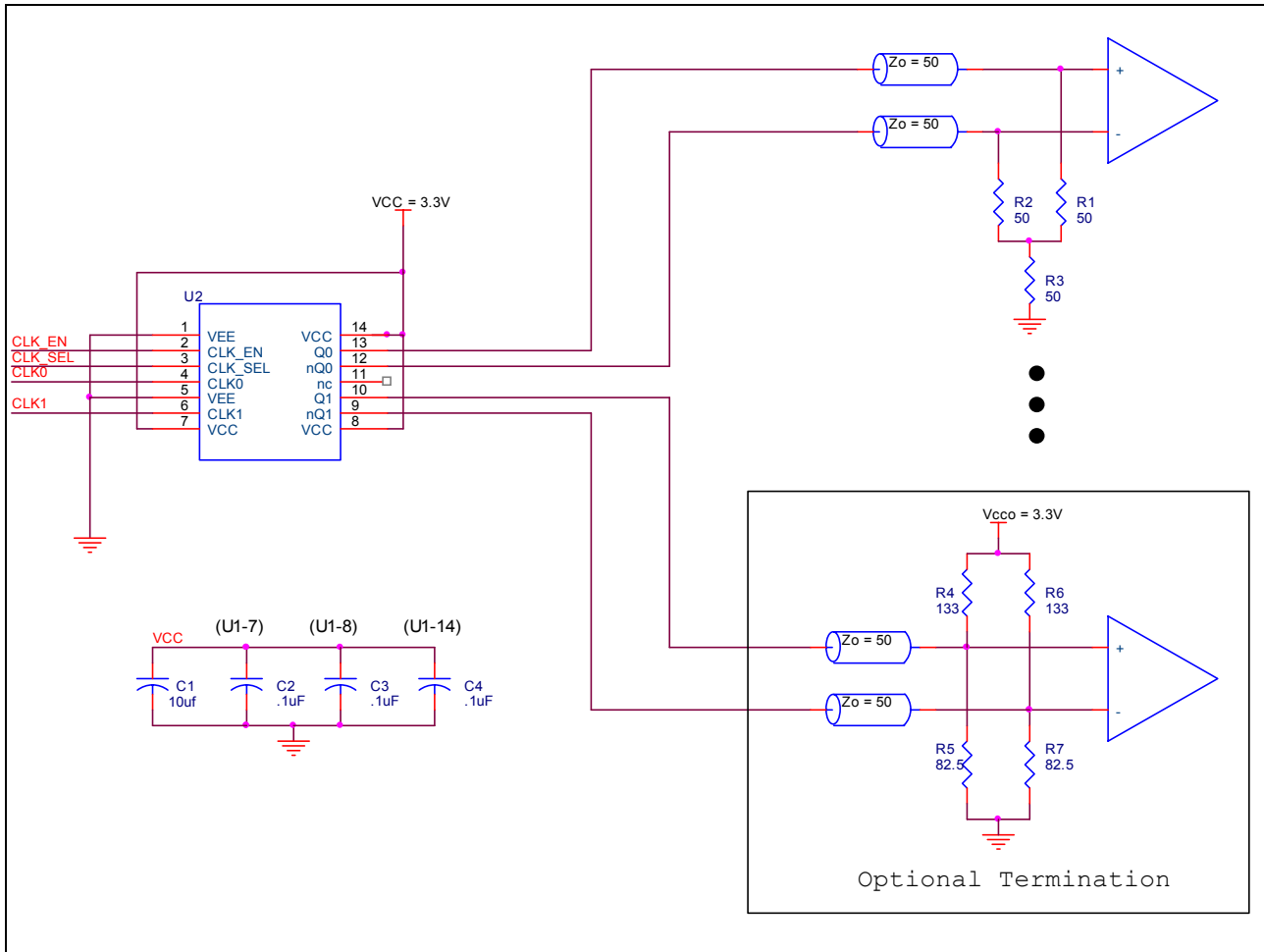


Figure 3. ICS8535I-21 LVPECL Buffer Schematic Example

## Power Considerations

This section provides information on power dissipation and junction temperature for the ICS8535I-21. Equations and example calculations are also provided.

### 1. Power Dissipation.

The total power dissipation for the ICS8535I-21 is the sum of the core power plus the power dissipated in the load(s). The following is the power dissipation for  $V_{CC} = 3.3V + 5\% = 3.465V$ , which gives worst case results.

NOTE: Please refer to Section 3 for details on calculating power dissipated in the load.

- Power (core)<sub>MAX</sub> =  $V_{CC\_MAX} * I_{EE\_MAX} = 3.465V * 50mA = 173.25mW$
- Power (outputs)<sub>MAX</sub> = **30mW/Loaded Output pair**  
If all outputs are loaded, the total power is  $2 * 30mW = 60mW$

**Total Power**<sub>MAX</sub> (3.3V, with all outputs switching) =  $173.25mW + 60mW = 233.25mW$

### 2. Junction Temperature.

Junction temperature,  $T_j$ , is the temperature at the junction of the bond wire and bond pad and directly affects the reliability of the device. The maximum recommended junction temperature for HiPerClockS devices is 125°C.

The equation for  $T_j$  is as follows:  $T_j = \theta_{JA} * Pd\_total + T_A$

$T_j$  = Junction Temperature

$\theta_{JA}$  = Junction-to-Ambient Thermal Resistance

$Pd\_total$  = Total Device Power Dissipation (example calculation is in section 1 above)

$T_A$  = Ambient Temperature

In order to calculate junction temperature, the appropriate junction-to-ambient thermal resistance  $\theta_{JA}$  must be used. Assuming no air flow and a multi-layer board, the appropriate value is 103.8°C/W per Table 6 below.

Therefore,  $T_j$  for an ambient temperature of 85°C with all outputs switching is:

$$85^\circ\text{C} + 0.233\text{W} * 103.8^\circ\text{C/W} = 109.2^\circ\text{C}. \text{ This is well below the limit of } 125^\circ\text{C}.$$

This calculation is only an example.  $T_j$  will obviously vary depending on the number of loaded outputs, supply voltage, air flow and the type of board (single layer or multi-layer).

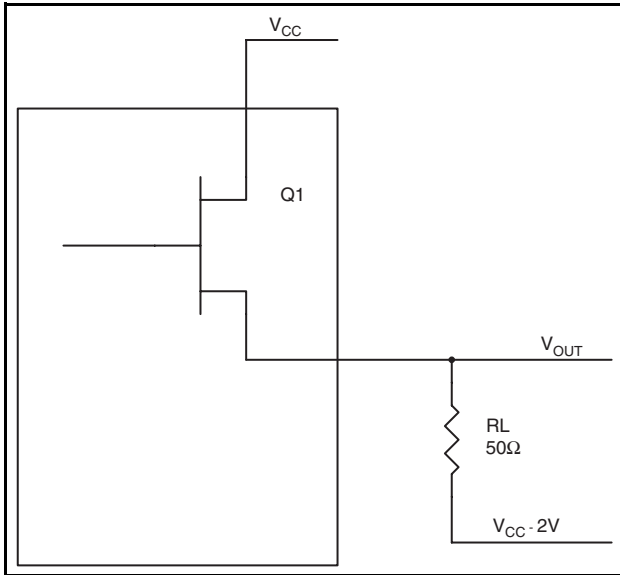
**Table 6. Thermal Resistance  $\theta_{JA}$  for 14 Lead TSSOP, Forced Convection**

Meters per Second	$\theta_{JA}$ vs. Air Flow		
	0	1	2.5
Multi-Layer PCB, JEDEC Standard Test Boards	103.8°C/W	99.6°C/W	97.3°C/W

### 3. Calculations and Equations.

The purpose of this section is to derive the power dissipated into the load.

LVPECL output driver circuit and termination are shown in *Figure 4*.



**Figure 4. LVPECL Driver Circuit and Termination**

To calculate worst case power dissipation into the load, use the following equations which assume a 50Ω load, and a termination voltage of  $V_{CC} - 2V$ .

- For logic high,  $V_{OUT} = V_{OH\_MAX} = V_{CC\_MAX} - 0.9V$   
 $(V_{CC\_MAX} - V_{OH\_MAX}) = 0.9V$
- For logic low,  $V_{OUT} = V_{OL\_MAX} = V_{CC\_MAX} - 1.7V$   
 $(V_{CC\_MAX} - V_{OL\_MAX}) = 1.7V$

$Pd\_H$  is power dissipation when the output drives high.

$Pd\_L$  is the power dissipation when the output drives low.

$$Pd\_H = [(V_{OH\_MAX} - (V_{CC\_MAX} - 2V))/R_L] * (V_{CC\_MAX} - V_{OH\_MAX}) = [(2V - (V_{CC\_MAX} - V_{OH\_MAX}))/R_L] * (V_{CC\_MAX} - V_{OH\_MAX}) = [(2V - 0.9V)/50\Omega] * 0.9V = \mathbf{19.8mW}$$

$$Pd\_L = [(V_{OL\_MAX} - (V_{CC\_MAX} - 2V))/R_L] * (V_{CC\_MAX} - V_{OL\_MAX}) = [(2V - (V_{CC\_MAX} - V_{OL\_MAX}))/R_L] * (V_{CC\_MAX} - V_{OL\_MAX}) = [(2V - 1.7V)/50\Omega] * 1.7V = \mathbf{10.2mW}$$

Total Power Dissipation per output pair =  $Pd\_H + Pd\_L = \mathbf{30mW}$

## Reliability Information

Table 7.  $\theta_{JA}$  vs. Air Flow Table for a 14 Lead TSSOP

$\theta_{JA}$ vs. Air Flow			
Meters per Second	0	1	2.5
Multi-Layer PCB, JEDEC Standard Test Boards	103.8°C/W	99.6°C/W	97.3°C/W

## Transistor Count

The transistor count for ICS8535I-21 is: 412

## Package Outline and Package Dimensions

Package Outline - G Suffix for 14 Lead TSSOP

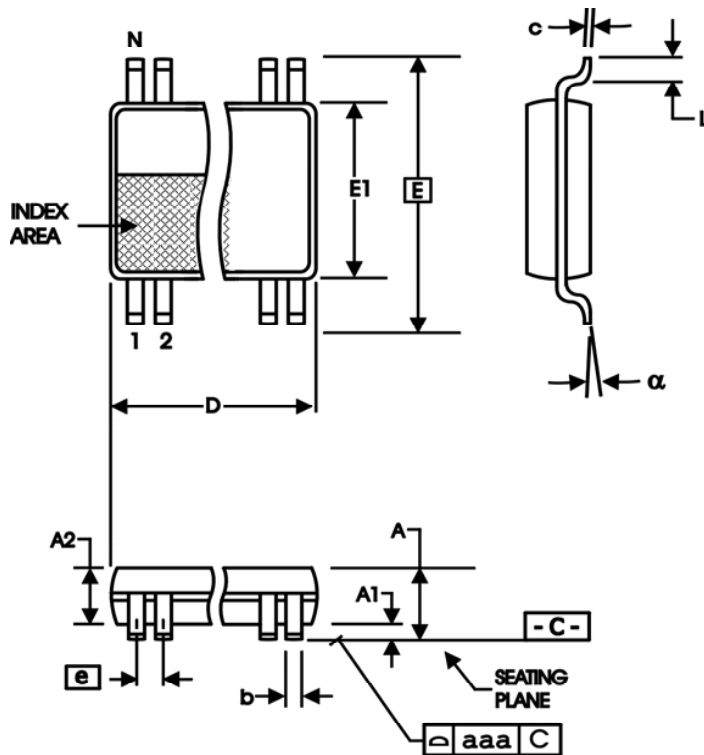


Table 8. Package Dimensions

All Dimensions in Millimeters		
Symbol	Minimum	Maximum
N	14	
A		1.20
A1	0.5	0.15
A2	0.80	1.05
b	0.19	0.30
c	0.09	0.20
D	4.90	5.10
E	6.40 Basic	
E1	4.30	4.50
e	0.65 Basic	
L	0.45	0.75
$\alpha$	0°	8°
aaa		0.10

Reference Document: JEDEC Publication 95, MO-153

## Ordering Information

Table 9. Ordering Information

Part/Order Number	Marking	Package	Shipping Packaging	Temperature
8535AGI-21LF	535AI21L	"Lead-Free" 14 Lead TSSOP	Tube	-40°C to 85°C
8535AGI-21LFT	535AI21L	"Lead-Free" 14Lead TSSOP	2500 Tape & Reel	-40°C to 85°C

NOTE: Parts that are ordered with an "LF" suffix to the part number are the Pb-Free configuration and are RoHS compliant.

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